

Notice of References Cited	Application/Control No. 10/705,756		Applicant(s)/Patent Under Reexamination FEE ET AL.	
	Examiner YONAS BAYOU		Art Unit 2434	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,389,540	05-2002	Scheifler et al.	726/21
*	B	US-6,044,467	03-2000	Gong, Li	726/4
*	C	US-2003/0220880	11-2003	Lao et al.	705/51
*	D	US-6,345,361	02-2002	Jerger et al.	726/3
*	E	US-6,704,804	03-2004	Wilson et al.	719/315
*	F	US-6,526,513	02-2003	Shrader et al.	726/4
*	G	US-6,138,238	10-2000	Scheifler et al.	726/17
*	H	US-5,915,085	06-1999	Koved, Lawrence	726/1
*	I	US-2003/0194085	10-2003	Dillaway, Blair B.	380/29
*	J	US-2003/0041267	02-2003	Fee et al.	713/201
*	K	US-2003/0061065	03-2003	Keeley, Damon A.J.	705/1
*	L	US-7,051,366	05-2006	LaMacchia et al.	726/14
*	M	US-7,076,557	07-2006	LaMacchia et al.	709/229

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.